

PBSS5440D

40 V PNP low V_{CEsat} (BISS) transistor Rev. 02 — 14 December 2009

Product data sheet

Product profile

1.1 General description

PNP low V_{CEsat} Breakthrough in Small Signal (BISS) single bipolar PNP transistor in a SOT457 (SC-74) SMD plastic package.

NPN complement: PBSS4440D.

1.2 Features

- Ultra low collector-emitter saturation voltage V_{CEsat}
- 4 A continuous collector current capability I_C (DC)
- Up to 15 A peak current
- Very low collector-emitter saturation resistance
- High efficiency due to less heat generation

1.3 Applications

- Power management functions
- Charging circuits
- DC-to-DC conversion
- MOSFET gate driving
- Power switches (e.g. motors, fans)
- Thin Film Transistor (TFT) backlight inverter

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{CEO}	collector-emitter voltage	open base		-	-	-40	V
I _C	collector current (DC)		[1]	-	-	-4	Α
I _{CM}	peak collector current	t = 1 ms or limited by $T_{j(max)}$		-	-	-15	Α
R _{CEsat}	collector-emitter saturation resistance	$I_C = -6 \text{ A};$ $I_B = -600 \text{ mA}$	[2]	-	55	75	mΩ

^[1] Device mounted on a ceramic Printed-Circuit Board (PCB), AL₂O₃, standard footprint.



^[2] Pulse test: $t_p \le 300 \ \mu s; \ \delta \le 0.02.$

Pinning information 2.

Table 2. **Pinning**

Pin	Description	Simplified outline	Symbol	
1	collector	D. D. D.		
2	collector	<u> </u>	1, 2, 5, 6 	
3	base		3 —	
4	emitter	1 12 13		
5	collector		4 sym030	
6	collector		cyccc	

Ordering information

Ordering information Table 3.

Type number	Package		
	Name	Description	Version
PBSS5440D	SC-74	plastic surface mounted package; 6 leads	SOT457

Marking 4.

Marking codes Table 4.

Type number	Marking code
PBSS5440D	71

Limiting values 5.

Table 5. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CBO}	collector-base voltage	open emitter	-	-40	V
V_{CEO}	collector-emitter voltage	open base	-	-40	V
V_{EBO}	emitter-base voltage	open collector	-	- 5	V
I _C	collector current (DC)		<u>[1]</u> -	-4	А
I _{CM}	peak collector current	t = 1 ms or limited by $T_{j(max)}$	-	–15	Α
I _B	base current (DC)		-	-0.8	Α
I _{BM}	peak base current	$t_p \le 300~\mu s$	-	-2	А
P _{tot}	total power dissipation	$T_{amb} \le 25 ^{\circ}C$	[2] _	360	mW
			[3] _	600	mW
			<u>[4]</u> _	750	mW
			[1] -	1.1	W
			[2][5]	2.5	W

2 of 13

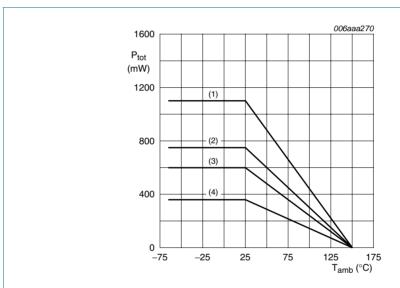
3 of 13

Table 5. Limiting values ... continued

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
T_{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	150	°C
T _{amb}	ambient temperature		–65	+150	°C

- Device mounted on a ceramic PCB, AL₂O₃, standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [3] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm².
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm².
- Operated under pulsed conditions: Duty cycle $\delta \le 10\%$ and pulse width $t_p \le 10$ ms.



- (1) Ceramic PCB, AL₂O₃, standard footprint
- (2) FR4 PCB, mounting pad for collector 6 cm²
- (3) FR4 PCB, mounting pad for collector 1 cm²
- (4) FR4 PCB, standard footprint

Fig 1. **Power derating curves**

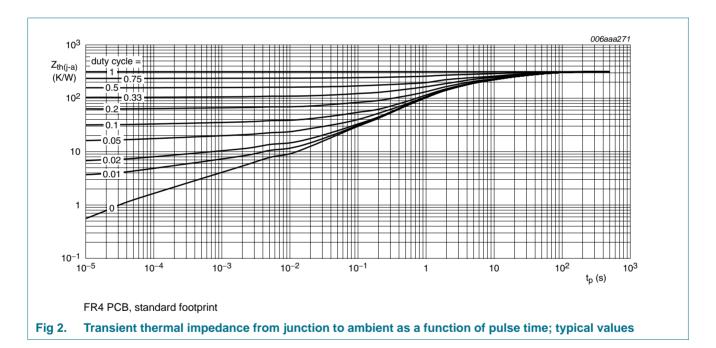
Product data sheet

6. Thermal characteristics

Table 6. Thermal characteristics

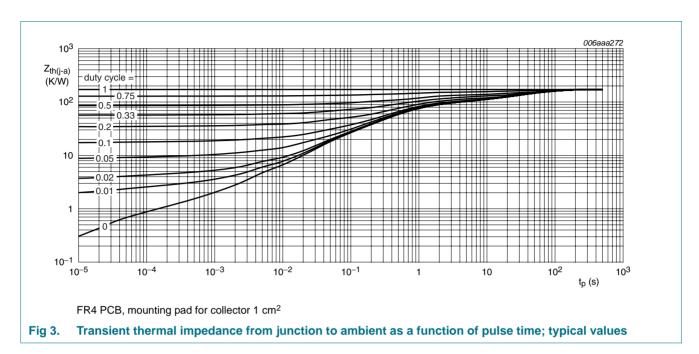
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	-	350	K/W
			[2] _	-	208	K/W
			[3] _	-	160	K/W
			[4]	113	K/W	
			[1][5]	-	50	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	45	K/W

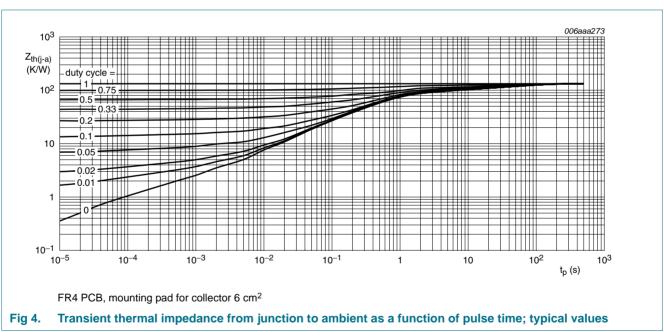
- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm².
- [3] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm².
- [4] Device mounted on a ceramic PCB, AL₂O₃, standard footprint.
- [5] Operated under pulsed conditions: Duty cycle $\delta \le 10\%$ and pulse width $t_p \le 10$ ms.



NXP Semiconductors PBSS5440D

40 V PNP low V_{CEsat} (BISS) transistor





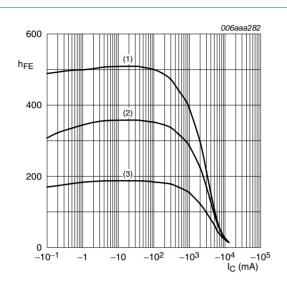
7. Characteristics

Table 7. Characteristics

 $T_{amb} = 25$ °C unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I _{CBO}	collector-base cut-off	$V_{CB} = -30 \text{ V}; I_E = 0 \text{ A}$		-	-	-0.1	μΑ
	current	$V_{CB} = -30 \text{ V}; I_E = 0 \text{ A}; T_j = 150 ^{\circ}\text{C}$		-	-	-50	μΑ
CES	collector-emitter cut-off current	$V_{CE} = -30 \text{ V}; V_{BE} = 0 \text{ V}$		-	-	-0.1	μΑ
ЕВО	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_C = 0 \text{ A}$		-	-	-0.1	μΑ
η _{FE}	DC current gain	$V_{CE} = -2 \text{ V}; I_{C} = -0.5 \text{ A}$		200	-	-	
		$V_{CE} = -2 \text{ V}; I_{C} = -1 \text{ A}$	[1]	200	-	-	
		$V_{CE} = -2 \text{ V}; I_{C} = -2 \text{ A}$	[1]	175	-	-	
		$V_{CE} = -2 \text{ V}; I_{C} = -4 \text{ A}$	[1]	80	-	-	
		$V_{CE} = -2 \text{ V}; I_{C} = -6 \text{ A}$	[1]	30	-	-	
V _{CEsat}	collector-emitter	$I_C = -0.5 \text{ A}; I_B = -50 \text{ mA}$		-	-46	-60	mV
saturation voltage	saturation voltage	$I_C = -1 A$; $I_B = -50 \text{ mA}$		-	-70	-110	mV
		$I_C = -2 \text{ A}; I_B = -200 \text{ mA}$		-	-120	-180	mV
		$I_C = -4 \text{ A}; I_B = -400 \text{ mA}$	[1]	-	-220	-300	mV
		$I_C = -6 \text{ A}; I_B = -600 \text{ mA}$	[1]	-	-320	-450	mV
R _{CEsat}	collector-emitter saturation resistance	$I_C = -6 \text{ A}$; $I_B = -600 \text{ mA}$	[1]	-	55	75	mΩ
V _{BEsat}	base-emitter	$I_C = -0.5 \text{ A}; I_B = -50 \text{ mA}$		-	-0.8	-0.85	V
	saturation voltage	$I_C = -1 \text{ A}; I_B = -50 \text{ mA}$		-	-0.84	-0.9	V
		$I_C = -1 A$; $I_B = -100 \text{ mA}$	[1]	-	-0.84	–1	V
		$I_C = -4 \text{ A}; I_B = -400 \text{ mA}$	[1]	-	-1.0	-1.1	V
V_{BEon}	base-emitter turn-on voltage	$V_{CE} = -2 \text{ V}; I_C = -2 \text{ A}$		-	-0.8	-1.0	V
t _d	delay time	$V_{CC} = -10 \text{ V}; I_C = -2 \text{ A};$		-	12	-	ns
r	rise time	$I_{Bon} = -0.1 \text{ A}$; $I_{Boff} = 0.1 \text{ A}$		-	43	-	ns
t _{on}	turn-on time			-	55	-	ns
t _s	storage time			-	240	-	ns
t _f	fall time			-	80	-	ns
off	turn-off time			-	320	-	ns
T	transition frequency	$V_{CE} = -10 \text{ V}; I_{C} = -0.1 \text{ A};$ f = 100 MHz		-	110	-	MHz
C _c	collector capacitance	$V_{CB} = -10 \text{ V}; I_E = i_e = 0 \text{ A};$ f = 1 MHz		-	50	-	pF

^[1] Pulse test: $t_p \le 300~\mu s;~\delta \le 0.02.$



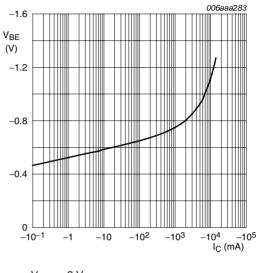
$$V_{CE} = -2 V$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

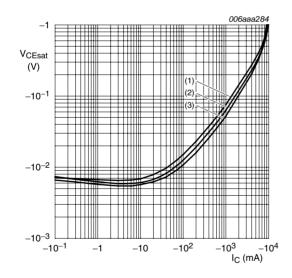
(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig 5. DC current gain as a function of collector current; typical values



$$V_{CE} = -2 \text{ V}$$
 $T_{amb} = 25 \text{ }^{\circ}\text{C}$

Fig 6. Base-emitter voltage as a function of collector current; typical values



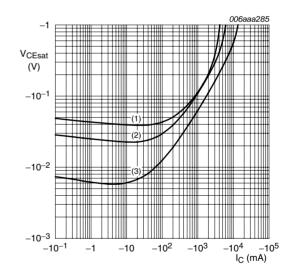
 $I_{\rm C}/I_{\rm B} = 20$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Collector-emitter saturation voltage as a Fig 7. function of collector current; typical values

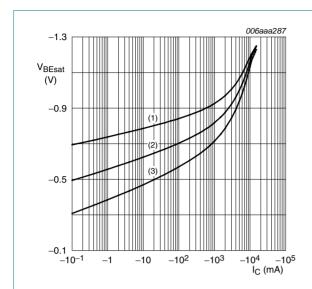


(1)
$$I_C/I_B = 100$$

(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

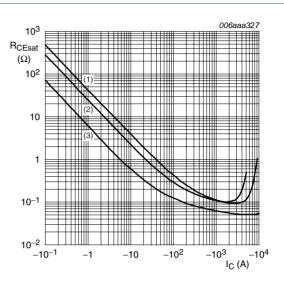
Fig 8. Collector-emitter saturation voltage as a function of collector current; typical values



$$I_{\rm C}/I_{\rm B} = 20$$

- (1) $T_{amb} = -55 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = 100 \, ^{\circ}C$

Fig 9. Base-emitter saturation voltage as a function of collector current; typical values



- (1) $I_C/I_B = 100$
- (2) $I_C/I_B = 50$
- (3) $I_C/I_B = 10$

Fig 10. Collector-emitter saturation resistance as a function of collector current; typical values

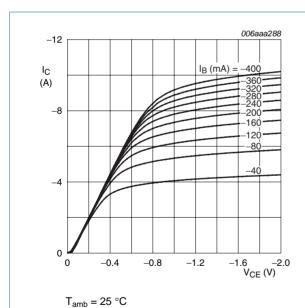
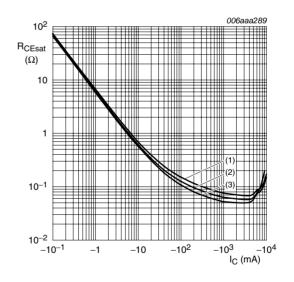


Fig 11. Collector current as a function of collector-emitter voltage; typical values



- $I_C/I_B = 20$
- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -55 \, ^{\circ}C$

Fig 12. Collector-emitter saturation resistance as a function of collector current; typical values

8. Test information

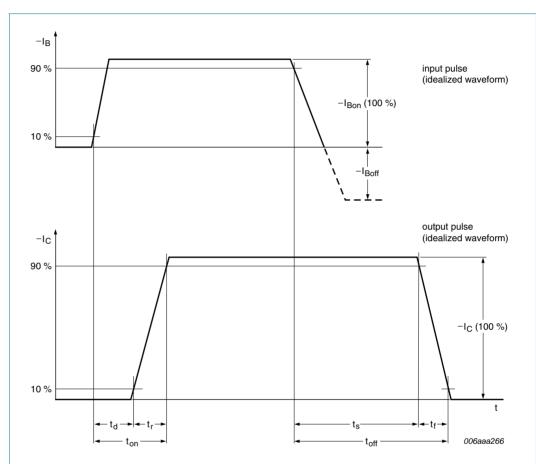
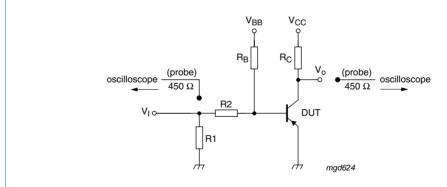


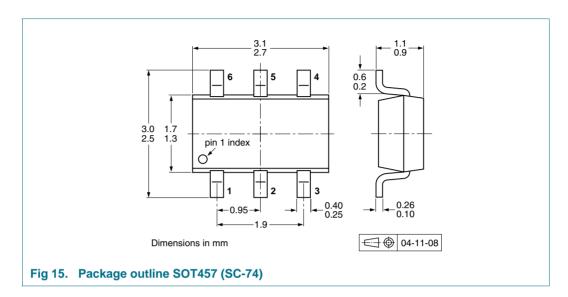
Fig 13. BISS transistor switching time definition



(1) $V_{CC} = -10 \text{ V}$; $I_{C} = -2 \text{ A}$; $I_{Bon} = -0.1 \text{ A}$; $I_{Boff} = 0.1 \text{ A}$

Fig 14. Test circuit for switching times

9. Package outline



10. Packing information

Table 8. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	Package	Description		Packing quant	ty	
				3000	5000	10000
PBSS5440D	SOT457	4 mm pitch, 8 mm tape and reel; T1	[2]	-115	-	-135
		4 mm pitch, 8 mm tape and reel; T2	[3]	-125	-	-165

[1] For further information and the availability of packing methods, see Section 13.

[2] T1: normal taping

[3] T2: reverse taping

11. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
Document 1D	Release date	Data Sheet Status	Change notice	Supersedes		
PBSS5440D_2	20091214	Product data sheet	-	PBSS5440D_1		
Modifications:		eet was changed to reflect v legal definitions and disc	1 ,	ne NXP Semiconductors, vere made to the technical		
	 Figure 2 "Tra typical values 		from junction to ambie	nt as a function of pulse time;		
	 Figure 3 "Transient thermal impedance from junction to ambient as a function of pulse time; typical values": updated 					
	 Figure 4 "Tra typical values 		from junction to ambie	nt as a function of pulse time;		
	 Figure 6 "Bas 	se-emitter voltage as a fur	ction of collector curre	nt; typical values": updated		
	• Figure 11 "Coupdated	ollector current as a function	on of collector-emitter v	voltage; typical values":		
PBSS5440D_1	20050427	Product data sheet	-	-		

NXP Semiconductors PBSS5440D

40 V PNP low V_{CEsat} (BISS) transistor

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

12.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

12.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental

damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

12.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

13. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PBSS5440D_2 © NXP B.V. 2010. All rights reserved.

NXP Semiconductors

PBSS5440D

40 V PNP low V_{CEsat} (BISS) transistor

14. Contents

1	Product profile
1.1	General description
1.2	Features
1.3	Applications
1.4	Quick reference data 1
2	Pinning information 2
3	Ordering information 2
4	Marking 2
5	Limiting values
6	Thermal characteristics 4
7	Characteristics 6
8	Test information 9
9	Package outline
10	Packing information 10
11	Revision history
12	Legal information 12
12.1	Data sheet status
12.2	Definitions
12.3	Disclaimers
12.4	Trademarks
13	Contact information 12
14	Contents

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.



